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Application/Control No.	Applicant(s)/Patent under Reexamination
09/876,183	CHANG ET AL.
Examiner	Art Unit
Hai L. Nguven	2816

SEARCHED				
Class	Subclass	Date	Examiner	
327 Î	2,3,5, 7-9,12	4/18/2005	HLN	
	238,244			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARC))
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